


<b>Search Notes</b>  	<b>Application/Control No.</b>  10708764	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN, HENG-CHIEN
	<b>Examiner</b>  Gauthier, Gerald	<b>Art Unit</b>  2614

SEARCHED			
Class	Subclass	Date	Examiner
455	575.01	10/25/2007	GG
			GG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB)	10/25/2007	GG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner